

ABSTRACT

A probe pin comprises a coil spring (3), a first plunger (1) including a major portion (11), a first elastic extension (12) and a second elastic extension (13), the first and the second elastic extensions (12, 13) extending from the major portion (11) in the same direction and a second plunger (2) forcedly inserted between the first and the second elastic extensions (12, 13). The first and the second plungers (1, 2) have electric conductivity, and the first and the second plungers (1, 2) are inserted from one and the other ends of the coil spring (3), respectively, so that the first and the second elastic extensions (12, 13) of the first plunger (1) hold the second plunger (2) with the first elastic extension (12) making a forced contact with a surface of the second plunger (2) to form thereat an electric connection between the first and the second plungers (1, 2).